

Notice of References CitedApplication/Control No.
09/704,641Applicant(s)/Patent Under
Reexamination
BIBERGER ET AL.Examiner
Ram N KackarArt Unit
1763

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,077,321	06-2000	Adachi et al.	29/25.01
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP 2000106358 A	04-2000	Japan	YASUDA, TORU	H01L 21/3065
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Edward Bok et al (Article Super critical Fluids for Single wafer Cleaning, Solid State Technology, June 1992)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.